



**AT&S**

# **ADVANCED IC SUBSTRATES FOR HETEROGENEOUS INTEGRATION**

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R&D, BU Microelectronics

March 15, 2023



# **PRESENTATION** **OUTLINE**

**Industry  
Trends**

**IC Substrates  
Drivers**

**AT&S  
Solutions**

**Summary**

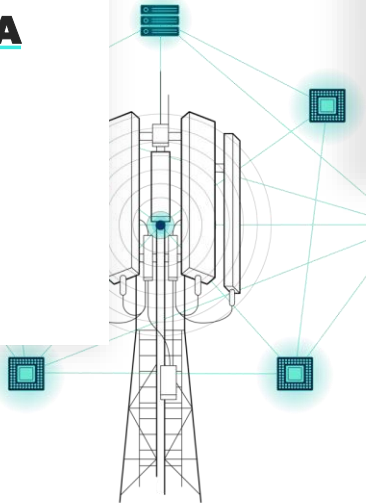
# DIGITALIZATION EVERYWHERE

## Data driven society

### THE RISE OF THE DATA ERA

#### Global Data Volume:

- 2020: 59 Zetabyte
- 2025: 175 Zetabyte  
→ (24% CAGR)



### Autonomous Driving

Cameras, Lidar,  
Radar

### Climate Research

Data generation and  
analytics

### Genomics

High performance  
computing for human  
genome sequencing

### Vision Processor

Augmented reality  
applications

Source: IDC (2019, 2020)

# **DATA GROWTH DRIVES COMPUTE, STORAGE, CONNECTIVITY & NETWORKING DEMAND**

- Technology changes
- Increased packaging solutions at system level
- There is NO standard technology which serves all application or customer needs and architecture.
- New module & system in packages driven by multiple new disruptive technologies

**“We are at the tip of an iceberg where we can go with packaging”**

Babak Sabi – Intel  
Corporate **VP Assembly and Test Technology Development Intel**

## **Data storage**

Server farms / data centers  
(e.g. server substrates)

- Solutions for increasing data speed (50gbit/second+)
- Reduced power consumption
- High level of integration and miniaturization

## **Data transfer**

Antennas (e.g. antenna modules, RF-modules, 5G communication, Car2Car, V2X)

- High end technologies for best in class signal integrity
- Low latency
- Higher bandwidth with new technical concepts

## **Data generation**

Sensors (e.g. mainboard, substrates for edge- & cloud computing)

- Ever-smaller L/S through innovative production processes (mSAP)
- Miniaturization and increased functionalities
- 140 GHz solutions for next generation radar applications

## **Data processing & analytics**

Devices (e.g. mainboard, substrates for edge- & cloud computing)

- Ever-smaller form factors
- Integration of advanced active and passive RF components
- High end technologies for best in class signal integrity

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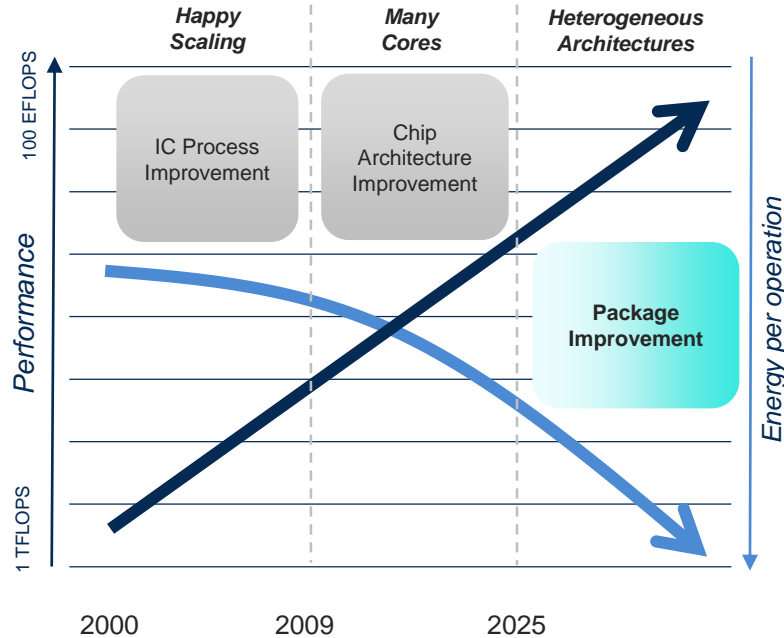
**IC Substrates  
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# FUTURE TREND FOR ADVANCED COMPUTING

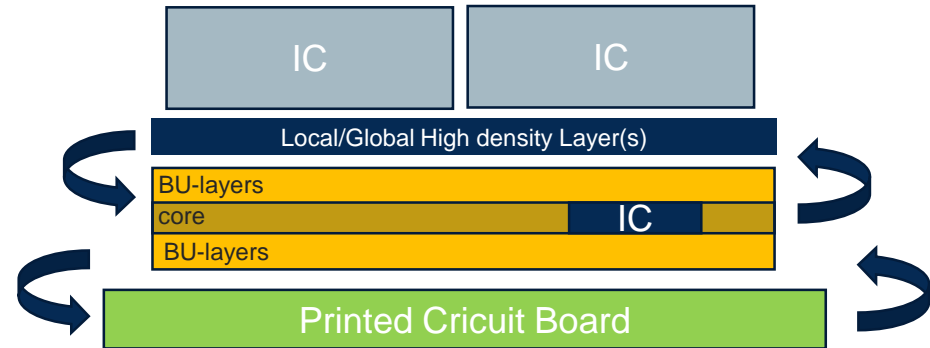
Node scaling alone does not provide desired performance



## Advanced Substrates & Packaging

New Challenging Functions in Packaging

- Larger Body Sizes (Chiplets, HIR)
- CTE Mismatch (Chiplets, Interposer)
- D2D Connection (BW, low latency)
- Power Delivery (Power Mgmt./conversion)
- Thermal Dissipation (Efficient Cooling)

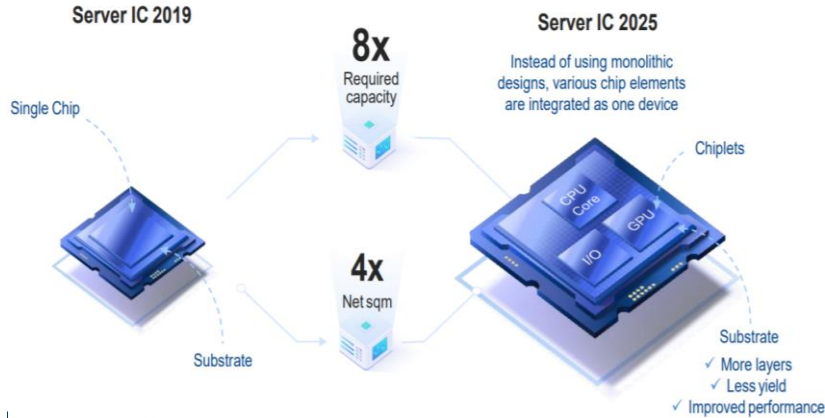


Which functions can/should be optimized where in the Package?



# ABF SUBSTRATES DRIVERS

## FCBGA Development trends



Drivers	Requirement trends
Heterogeneous integration	Large body/package size (up to 100x100)
High I/o COUNT	High layer count >20L
High-density interconnect	L/S 9/12μm
Bump pitch	90μm and below
Increase bandwidth	High-speed transmission
Increase assembly yield	Low warpage
More functionalities	Thermal management

## What else can be done with IC Substrates?

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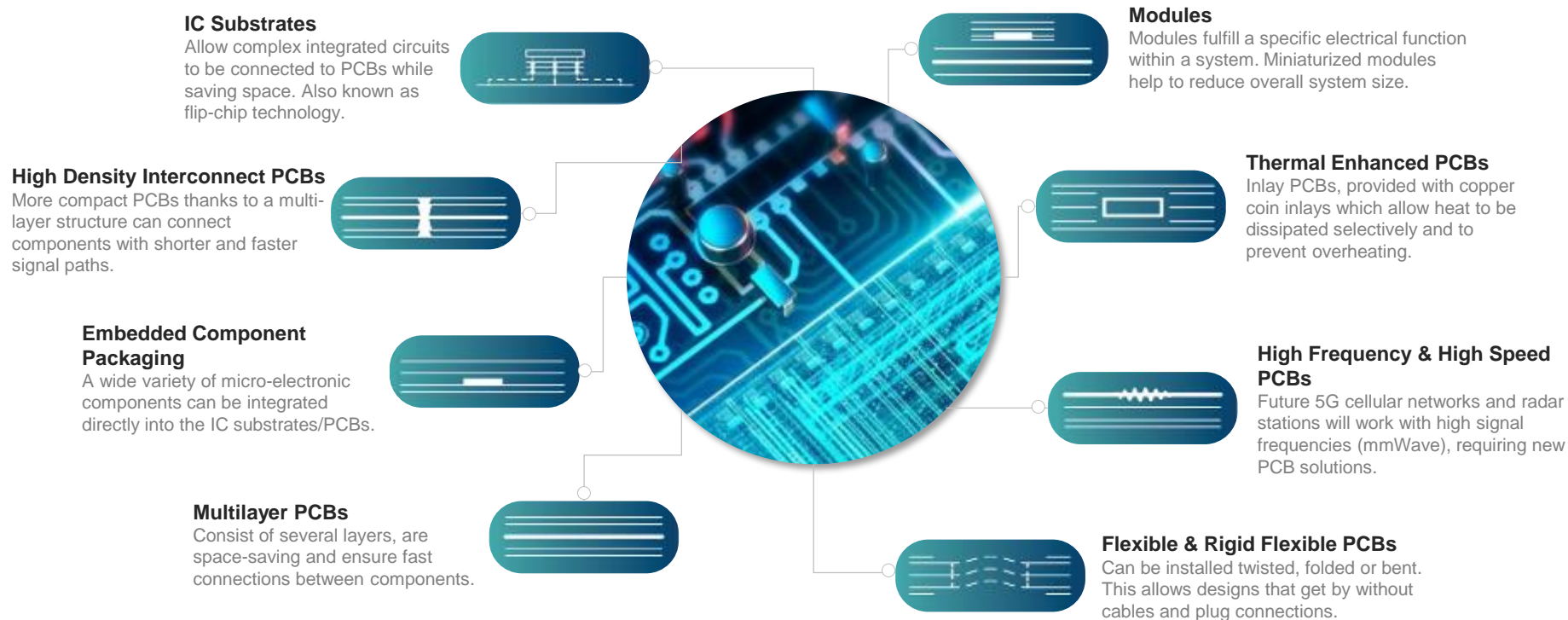
**AT&S  
Solutions**

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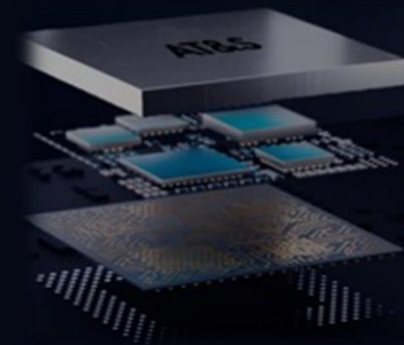
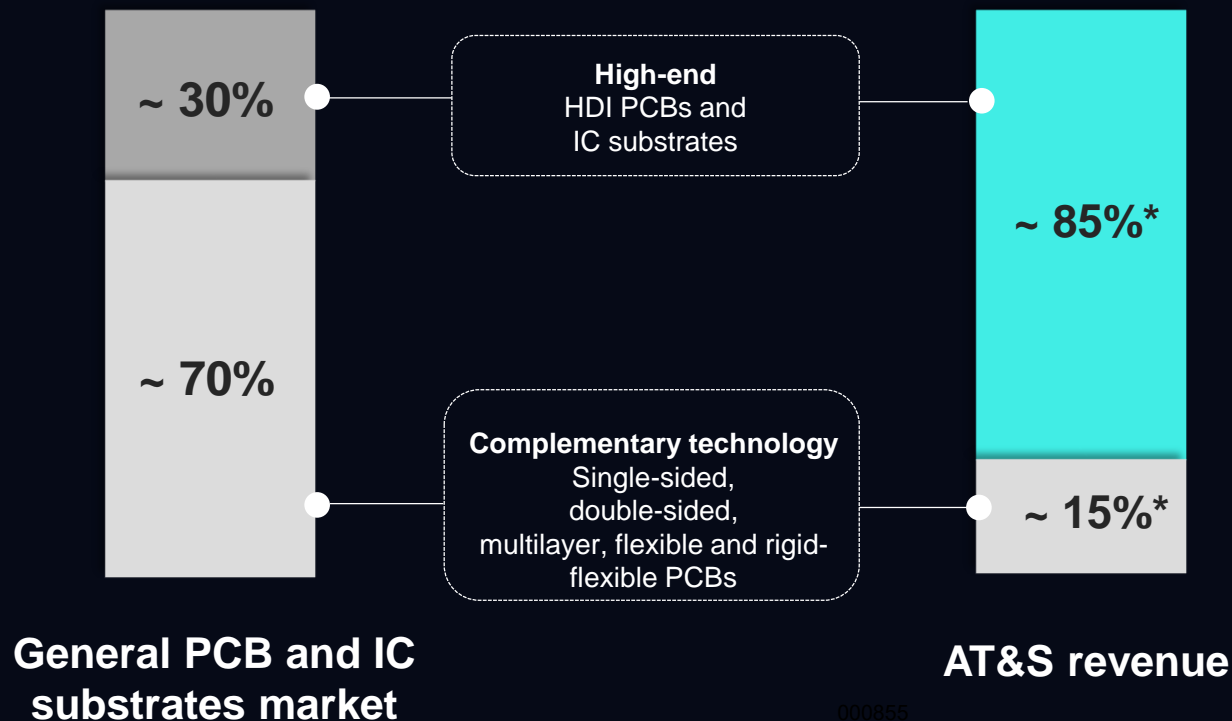


# AT&S PRODUCT PORTFOLIO

## Wide range of products for interconnection solutions



# STRATEGIC FOCUS ON HIGH-END TECHNOLOGIES



# **R&D PROGRAMS FOCUSING ON THE MAJOR TRENDS**

Innovation focused on major trends and industry needs



## **Miniaturization**

Increased computing power for fast data processing



## **Modularization**

More functionality at same or reduced space



## **Increased speed / Low latency**

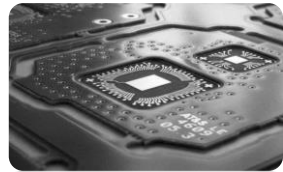
Communication of high data volumes (5G, Autonomous Driving)



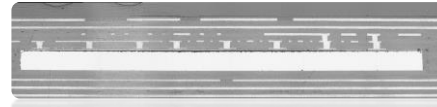
## **Increased power / Power efficiency**

Reducing non-value adding electrical loss

# ADVANCED PACKAGING CONCEPTS ON LARGE PANELS

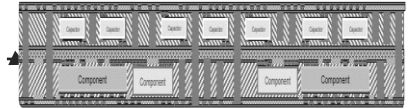


**Cavities**  
THK reduction

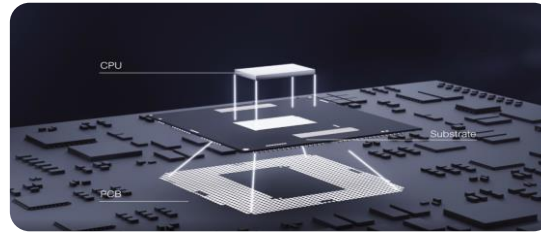


ECP® - 256 Id ePMIC IC embedded  
pkg

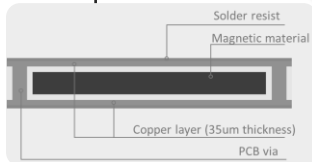
**ECP**  
Passive/Active  
embedding



**Multilayer PCB**  
Multi Functional Core



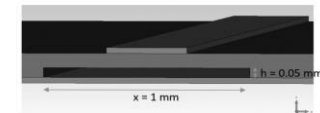
**IC Substrate**



**Embedded Magnetic Material**

**Magnetics**  
Inductors/Shielding

**SIW**  
Substrate Integrated  
Waveguides

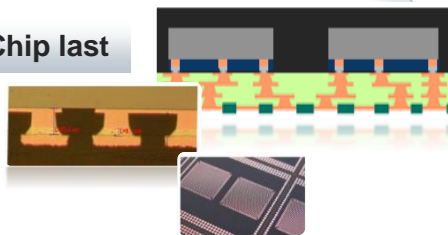


**75µm Dielectric Material**  
**50µm Air Gap**

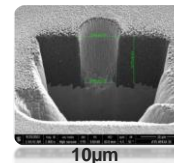
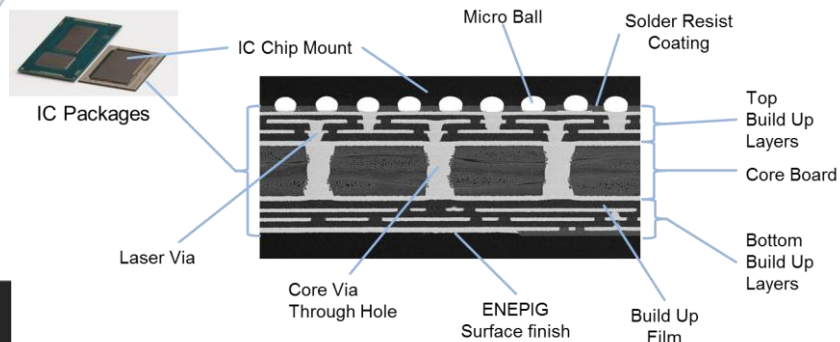
## Small Via and High Density Routing



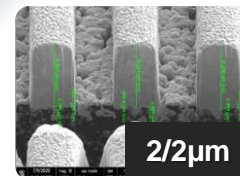
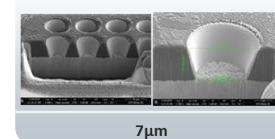
- Package Size: 15x15mm
- 2 components / PKG
- Component Size: 6x6mm
- Component I/O: 1089
- Component Pad: 83µm
- Laser via: 30µm
- Line/ Space: 9/12µm



**Carries the IC chips and transmits the signals from the IC chips to the PCB**



## PID



# EMBEDDING OF COMPONENTS

Reliability test TV : MRT 10x, TCT 750cycle and uHAST 100hr → **No blister/delamination, R shift < 6%**

## General package information:

- 6 Layer
- L/S: 9/12 $\mu$ m
- Via: 30 $\mu$ m
- Core thickness: 200 $\mu$ m
- 2 dies embedded



Symmetric BU : n-2-n structure with ECP®



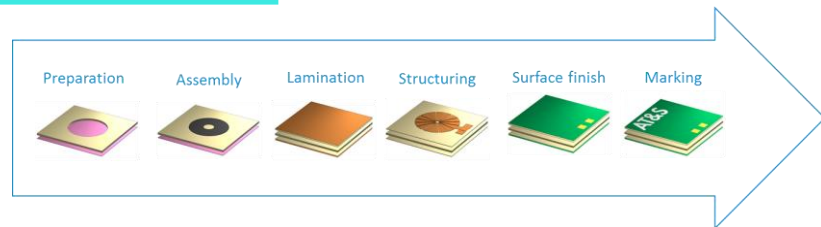
MSL3(Pre-condition), MRT 10X, TCT 750 cycles & uHAST test results : **Passed**

Test item	Standard	Failure mode	Pre-conditioning	Rel. Conditions
Multi Reflow	IPC/JEDEC J-STD-020D.1	Visual check Cross section analysis E-test	125°C 24hrs, 60°C/60%RH for 40hrs, 3x Reflow(260°C peak)	Reflow peak max 260°C, 10x (10 reflow cycles)
TCT	IPC TM650 2.6.2.7	Visual check Cross section analysis E-test		-55°C/+125°C, 750cycle (Readout at 250/500/750)
uHAST	JEDEC JESD22-A110E	Visual check Cross section analysis E-test		130°C/85%RH, 100hr (Readout at 50/100)

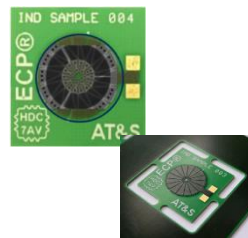
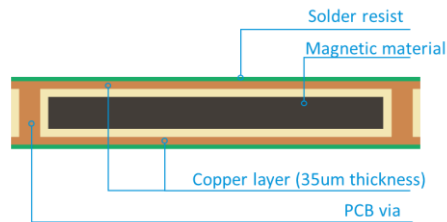


# EMBEDDING OF MAGNETIC MATERIALS

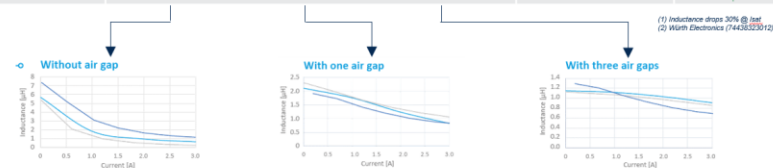
- Qualified process based on the ECP® technology
- Independent from layer count
- Can be applied to PCBs and Cores of ICS



Inductor	Value	Unit
Cu THK	35	μm
Magnetic Material THK	0.3	mm
Inner/outer diameter	3/10.5	mm
Windings	16	turns
Total thickness	0.5	mm
Inductance	5.7-1.15	μH
Saturation Current	0.3-3.6	A



Parameter	Symbol	Without air gap	With 1 air gap	With 3 air gaps	Standard SMD (2)	Benchmark
Inductance	$L$ (@ 1 MHz)	5.7 μH	2.2 μH	1.15 μH	1.2 μH	Equal
Saturation current	$I_{sat}$ (1)	300 mA	1.5 A	3.6 A	3.8 A	Equal
Rated current (DC)	$I_R$ (@ $\Delta T = 40$ K)		2.0 A		1.9 A	Equal
DC Resistance	$R_{DC}$ (@ 0.1 A)		79 mΩ		82 mΩ	Equal
Self-resonance fr.	$f_{res}$	30 MHz	40 MHz	80 MHz	75 MHz	Equal
Package size	$D_I/D_O$		3/10.5 mm		2.5 x 2 mm	
Air gap length	$l_g$	-	500 μm	3 x 170 μm	-	
Total thickness	$h$		500 μm		1 mm	



Source: AT&amp;S AG

# **CONCETS FOR LOSS REDUCTION**

## **Solutions to improve Signal Integrity Performance**

### **Loss factor Base Material (Dielectric Losses)**

- Suitable Materials

### **Length of Traces (Conductor Losses)**

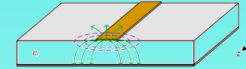
- Miniaturization (L/S)

### **Skin Effect (Ohmic load)**

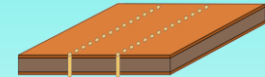
- Low Copper Foil Treatment (low / no profile)
- Smooth Traces (Adhesion Promoter)
- Suitable End Surface Platings (Ni less ...)



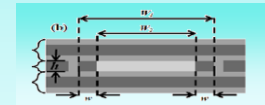
### **Micro Strip line**



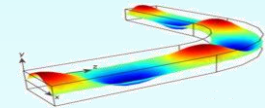
### **Substrate Integrate Waveguide**



### **Air filled Waveguide**



### **Waveguide**

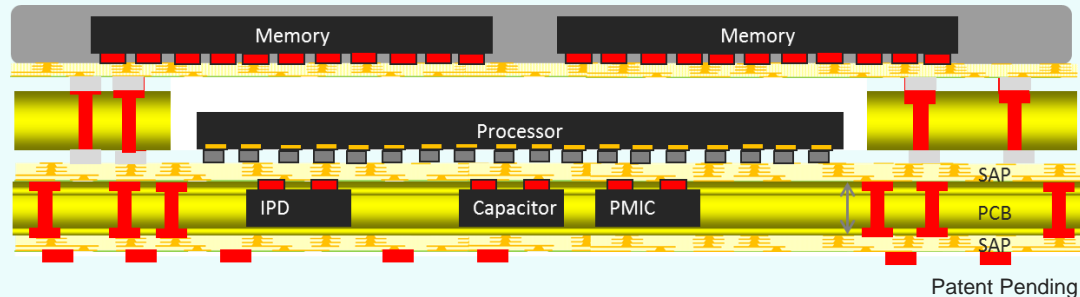


# COMBINATION OF DIFFERENT CONCEPTS

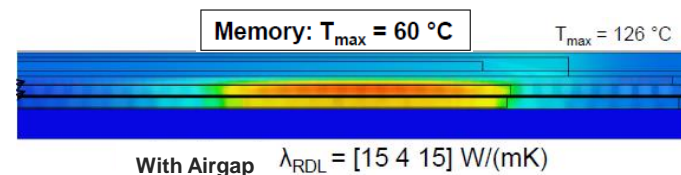
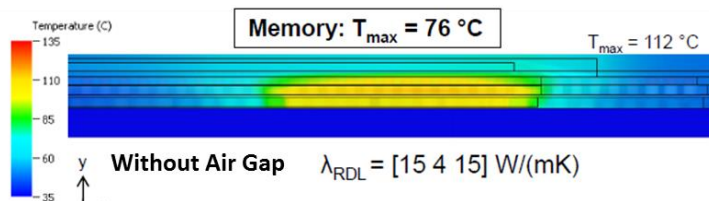
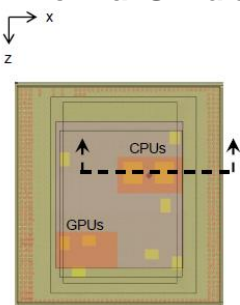
## Chip First + Chip last + AirGap

### Computing/Processing Module with:

- Integrated power supply
- Solution to connect processor and memory in a PoP structure (if needed)
- Integrated signal stabilization
- Potential for additional functionality (communication, anti-fraud, etc.)
- Improved Thermal Management



### Thermal Simulation



### Conditions in package improved due to air gap

- Temperature of memory decreases (76°C to 60°C)
- Temperature of Processor increases (112°C to 126°C) → can be decreased with tool box

Source: AT&S AG

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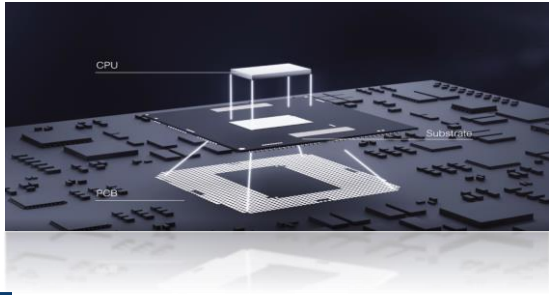
# SUMMARY & CONCLUSION

## New Interconnect Requirements drive Advance Packaging Solutions

- Increased packaging solutions at system level integration are required
- Miniaturization of electronic systems drives the need for larger, multi-functional modules
- The IC Substrate is a major building block in nearly all advanced system architectures

## PCB/IC Substrate Technologies offer a versatile Tool Box

- Fan-Out capabilities for fine pitch components enable chip first and chip last integration
- Magnetic materials can be embedded for various functions (Inductor, shielding, etc.)
- New concepts offer improved Signal Integrity
- Advanced Cooling concepts use Copper plated vias, cavity walls and inlays



# **THANK YOU!**

For more information:

## **R&D Collaboration:**

- Markus Leitgeb [m.leitgeb@ats.net](mailto:m.leitgeb@ats.net)

## **Business Development:**

- Venkata Mokkapati [v.mokkapati@ats.net](mailto:v.mokkapati@ats.net)

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Summary



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